# MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

# 20N04-MS

# **Product specification**



# 20N04-MS

www.msksemi.com

# Description

The 20N04-MS is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The 20N04-MS meet the RoHS and Green Product requirement, 100% EAS guaranteed with full

### FEATURE

- 100% EAS Guaranteed
- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

### **Reference News**

PACKAGE OUTLINE	PIN CONFIGURATION	Marking
SOT-89	G	20N04

### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
Vds	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
lo@Ta=25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	15	А
lo@Ta=70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	7.5	A
Ідм	Pulsed Drain Current <sup>2</sup>	22	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	22	mJ
las	Avalanche Current	23	A
PD@Ta=25°C	Total Power Dissipation <sup>4</sup>	1.5	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

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# **Product Summary**

BVDSS	40V
RDSON	15mΩ
ID	20A



# SEMICONDUCTOR

### Thermal Data

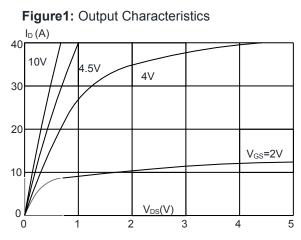
Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction-ambient <sup>1</sup>		62	°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>		2.8	°C/W

#### N-Channel Electrical Characteristics (TJ=25°Cunless otherwise specified)

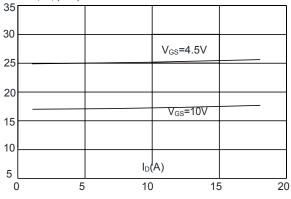
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charact	teristic					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage V <sub>GS</sub> =0V, I <sub>D</sub> =250µA		40	-	-	V
DSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V	-	-	1.0	μA
lgss	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
On Charact	teristics					
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA	1.0	1.5	2.5	V
<b>D</b>	Static Drain-Source on-Resistance	Vgs=10V, ID=8A	-	15	20	mΩ
$R_{DS(on)}$	note3	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A	-	18	25	mΩ
Dynamic C	haracteristics					
Ciss	Input Capacitance		-	633	-	pF
Coss	Output Capacitance	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, f=1.0MHz	-	67	-	pF
Crss	Reverse Transfer Capacitance		-	58	-	pF
Qg	Total Gate Charge	VDS=20V, ID=8A,	-	12	-	nC
Qgs	Gate-Source Charge	$V_{GS}=20V$ , ID-6A, $V_{GS}=10V$	-	3.2	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	3.1	-	nC
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-on Delay Time		-	4	-	ns
tr	Turn-on Rise Time	$V_{DD}$ = 20V, R <sub>L</sub> =2.5 $\Omega$	-	3	-	ns
$t_{d(off)}$	Turn-off Delay Time	$V_{GS}$ = 10V, $R_{REN}$ = 3 $\Omega$	-	15	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	2	-	ns
Drain-Sour	ce Diode Characteristics and Maximu	m Ratings				
ls	Maximum Continuous Drain to Source Diode Forward Current		-	-	35	А
Іѕм	Maximum Pulsed Drain to Source Diode Forward Current		-	-	40	Α
Vsd	Drain to Source Diode Forward Voltage		-	-	1.2	V



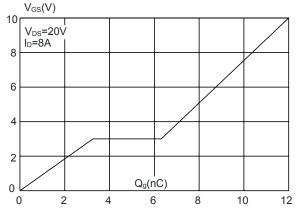
### **Typical Performance Characteristics-N**



**Figure 3:**On-resistance vs. Drain Current RDS(ON) (mΩ)







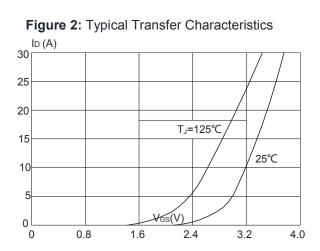
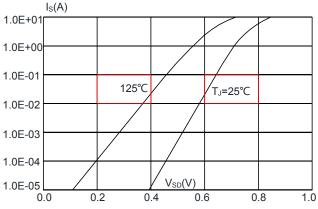


Figure 4: Body Diode Characteristics





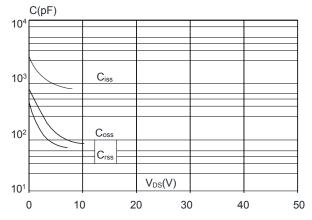




Figure 7: Normalized Breakdown Voltage vs.

Junction Temperature

Figure 9: Maximum Safe Operating Area

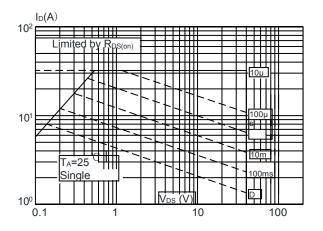
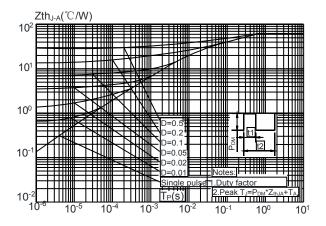
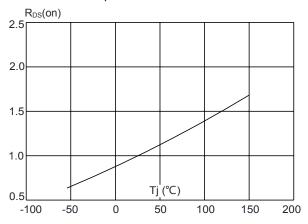


Figure.11: Maximum Effective

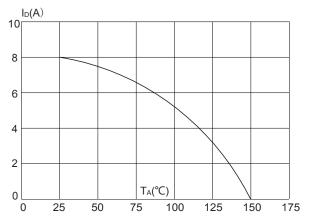
Transient Thermal Impedance, Junction-to-Ambient



**Figure 8:** Normalized on Resistance vs. Junction Temperature

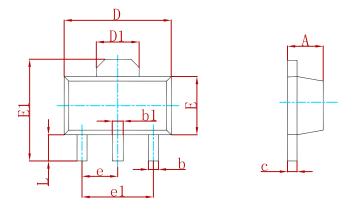


**Figure 10:** Maximum Continuous Drain Current vs. Ambient Temperature



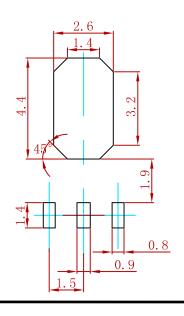


#### PACKAGE MECHANICAL DATA



Symbol	Dimensions In Millimeters		Dimensions In Inches	
Symbol	Min	Max	Min	Max
A	1.400	1.600	0.055	0.063
b	0.320	0.520	0.013	0.020
b1	0.400	0.580	0.016	0.023
С	0.350	0.440	0.014	0.017
D	4.400	4.600	0.173	0.181
D1	1.550 REF.		0.061 REF.	
E	2.300	2.600	0.091	0.102
E1	3.940	4.250	0.155	0.167
е	1.500 TYP.		1.500 TYP. 0.060 TYP.	
e1	3.000 TYP.		0.118	STYP.
L	0.900	1.200	0.035	0.047

### Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:±0.05mm.

3. The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
20N04-MS	SOT-89	1000

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